File No.: 521.41463X00 Client Ref.: PHCF-01103

IN THE CLAIMS:

Please amend the claims as follows:

(Currently Amended) A crystalline silicon thin film semiconductor photovoltaic

device comprising:

a conductive substrate or a substrate having on its surface a conductive layer;

a crystallographically oriented first polycrystalline silicon layer, which has

been formed by introducing a metal catalyst element (i) into, or (ii) so as to come into

contact with a surface portion of, an amorphous silicon layer, the amorphous silicon

layer being formed on the surface of the conductive substrate or the conductive

layer, and heat treating the amorphous silicon layer to crystallize the amorphous

silicon layer that is formed on the conductive substrate or the conductive layer, and

that includes a substantial amount of metal catalyst element at an outermost surface

of the first polycrystalline silicon layer on the side of the conductive substrate or the

conductive layer and only a trace amount of the metal catalyst element elsewhere

within the first polycrystalline silicon layer; and

a second polycrystalline silicon layer that is formed on the first polycrystalline

silicon layer and that has which has been formed without catalytic effect, using the

first polycrystalline silicon layer as a seed crystal, so as to have the same

conductivity type as the first polycrystalline silicon layer.

2. (Currently Amended) The crystalline silicon thin film semiconductor

photovoltaic device according to claim 1, wherein the second polycrystalline silicon

layer contains not less than 0.1% of hydrogen.

File No.: 521.41463X00

Client Ref.: PHCF-01103

3. (Currently Amended) The crystalline silicon thin film semiconductor photovoltaic device according to claim 1, wherein the second polycrystalline silicon layer is crystallographically oriented in the thickness wise direction.

- 4. (Currently Amended) The crystalline silicon thin film semiconductor photovoltaic device according to claim 1, wherein the second polycrystalline silicon layer has the same crystallographic orientation as the first polycrystalline silicon layer.
- 5. (Currently Amended) The crystalline silicon thin film semiconductor photovoltaic device according to claim 1, which further comprises, provided on the second polycrystalline silicon layer in its side remote from the first polycrystalline silicon layer, a third polycrystalline silicon layer of a second conductivity type which is different from the conductivity type of the second polycrystalline silicon layer.
- 6. (Currently Amended) The crystalline silicon thin film semiconductor photovoltaic device according to claim 5, which further comprises, provided between the third polycrystalline silicon layer and the second polycrystalline silicon layer, a fourth polycrystalline silicon layer of a third conductivity type which is different from the conductivity type of the second polycrystalline silicon layer and the conductivity type of the third polycrystalline silicon layer.

File No.: 521.41463X00 Client Ref.: PHCF-01103

7. (Currently Amended) The crystalline silicon thin film semiconductor

photovoltaic device according to claim 5, wherein the third polycrystalline silicon

layer has the same crystallographic orientation as the second polycrystalline silicon

layer.

8. (Currently Amended) The crystalline silicon thin film semiconductor

photovoltaic device according to claim 6, wherein the fourth polycrystalline silicon

layer has the same crystallographic orientation as the second polycrystalline silicon

layer.

9. (Currently Amended) The crystalline silicon thin film semiconductor

photovoltaic device according to claim 6, wherein the fourth polycrystalline silicon

layer has the same crystallographic orientation as the third polycrystalline silicon

layer.

10. (Currently Amended) The crystalline silicon thin film semiconductor

photovoltaic device according to claim 5, wherein the third and fourth polycrystalline

silicon layers contain not less than 0.1% of hydrogen.

11. (Previously Presented) A crystalline silicon thin film photovoltaic device

comprising:

a conductive substrate or an insulating substrate having on its surface a

conductive layer;

File No.: 521.41463X00 Client Ref.: PHCF-01103

a first polycrystalline silicon layer of a first conductivity type which has been

formed by introducing a metal catalyst element (i) into, or (ii) so as to come into

contact with a surface portion of, an amorphous silicon layer, the amorphous silicon

layer being formed on the surface of the conductive substrate or the conductive

layer, and heat treating the amorphous silicon layer to crystallize the amorphous

silicon layer;

a second polycrystalline silicon layer which has been formed without catalytic

effect, using the first polycrystalline silicon layer as a seed crystal, so as to have the

same conductivity type as the first conductivity type;

a substantially i-type third polycrystalline silicon layer formed, without catalytic

effect, on the second polycrystalline silicon layer;

a fourth polycrystalline silicon layer that is formed, without catalytic effect, on

the third polycrystalline silicon layer and is of a second conductivity type which is

different from the first conductivity type; and

an electrode part provided on the fourth polycrystalline silicon layer.

12. (Original) The crystalline silicon thin film photovoltaic device according to

claim 11, wherein:

the conductive substrate is stainless steel; and

the substrate having on its surface a conductive layer is glass.

13. (Previously Presented) A crystalline silicon thin film photovoltaic device

comprising:

an insulating substrate having on its surface an electrode;

PATENT

Our Ref.: 3008-0034 File No.: 521.41463X00

Client Ref.: PHCF-01103

a first polycrystalline silicon layer of a first conductivity type which has been

formed by introducing a metal catalyst element (i) into, or (ii) so as to come into

contact with a surface portion of, an amorphous silicon layer, the amorphous silicon

layer being formed on the electrode of the insulating substrate, and heat treating the

amorphous silicon layer to crystallize the amorphous silicon layer;

a second polycrystalline silicon layer which has been formed without catalytic

effect, using the first polycrystalline silicon layer as a seed crystal, so as to have the

same conductivity type as the first conductivity type;

a third polycrystalline silicon layer which is formed without catalytic effect on

the second polycrystalline silicon layer and is of a second conductivity type which is

different from the first conductivity type; and

an electrode part provided on the third polycrystalline silicon layer.

14. (Cancelled)

15. (Cancelled)

16. (Cancelled)

17. (Currently Amended) A crystalline silicon thin film semiconductor

photovoltaic device, comprising:

a conductive substrate or a substrate having on its surface a conductive layer;

a first polycrystalline silicon layer having a first connectivity type, formed of (i)

an amorphous silicon layer disposed on the surface of the conductive substrate or

File No.: 521.41463X00 Client Ref.: PHCF-01103

the conductive layer, and (ii) a metal catalyst element introduced into, or into contact with a surface portion of, the amorphous silicon layer, with the amorphous silicon layer <u>being crystallized</u> erystallize by heat treatment; and

a second polycrystalline silicon layer, having the same conductivity type as the first polycrystalline silicon layer, and being formed using the first polycrystalline silicon layer as a seed crystal.

18. (Currently Amended) The crystalline silicon thin film semiconductor photovoltaic device according to claim 17, wherein:

the second polycrystalline silicon layer is formed by plasma CVD.

19. (Currently Amended) The crystalline silicon thin film semiconductor photovoltaic device according to claim 17, wherein:

the second polycrystalline silicon layer is formed at a temperature of approximately 300° C or less.

20. (Currently Amended) The crystalline silicon thin film semiconductor photovoltaic device according to claim 17, wherein:

the first polycrystalline silicon layer includes a substantial amount of the metal catalyst element at a surface of the of the first polycrystalline silicon layer proximate to the conductive substrate or the conductive layer and only a trace amount of the metal catalyst element elsewhere second polycrystalline silicon layer is formed without the metal catalyst element in the first polycrystalline silicon layer acting as a catalyst in the formation of the second polycrystalline silicon layer.

File No.: 521.41463X00

Client Ref.: PHCF-01103

21. (New) A crystalline silicon thin film photovoltaic device comprising:

a conductive substrate or a substrate having on its surface a conductive layer;

a crystallographically oriented first polycrystalline silicon layer containing a

metal catalyst element transformed from an amorphous silicon layer, the first

polycrystalline silicon layer being formed on the surface of the conductive substrate

or the conductive layer; and

a second polycrystalline silicon layer formed by using the first polycrystalline

silicon layer as a seed crystal, the second polycrystalline silicon layer containing no

metal catalyst element and having the same conductivity type as the first

polycrystalline silicon layer.

22. (New) The crystalline silicon thin film photovoltaic device according to

claim 21, wherein the second polycrystalline silicon layer contains not less than 0.1%

of hydrogen.

23. (New) The crystalline silicon thin film photovoltaic device according to

claim 21, wherein the second polycrystalline silicon layer is crystallographically

oriented in the thickwise direction.

24. (New) The crystalline silicon thin film photovoltaic device according to

claim 21, wherein the second polycrystalline silicon layer has the same

crystallographic orientation as the first polycrystalline silicon layer.

File No.: 521.41463X00 Client Ref.: PHCF-01103

25. (New) The crystalline silicon thin film photovoltaic device according to claim 21, which further comprises, provided on the second polycrystalline silicon

layer in its side remote from the first polycrystalline silicon layer, a third

polycrystalline silicon layer of a second conductivity type which is different from the

conductivity type of the second polycrystalline silicon layer, the third polycrystalline

silicon layer containing no metal catalyst element.

26. (New) The crystalline silicon thin film photovoltaic device according to

claim 25, which further comprises, provided between the third polycrystalline silicon

layer and the second polycrystalline silicon layer, a fourth polycrystalline silicon layer

of a third conductivity type which is different from the conductivity type of the second

polycrystalline silicon layer and the conductivity type of the third polycrystalline

silicon layer, the fourth polycrystalline silicon layer containing no metal catalyst

element.

27. (New) The crystalline silicon thin film photovoltaic device according to

claim 25, wherein the third polycrystalline silicon layer has the same crystallographic

orientation as the second polycrystalline silicon layer.

28. (New) The crystalline silicon thin film photovoltaic device according to

claim 26, wherein the fourth polycrystalline silicon layer has the same

crystallographic orientation as the second polycrystalline silicon layer.

File No.: 521.41463X00 Client Ref.: PHCF-01103

29. (New) The crystalline silicon thin film photovoltaic device according to claim 28, wherein the fourth polycrystalline silicon layer has the same crystallographic orientation as the third polycrystalline silicon layer.

30. (New) The crystalline silicon thin film photovoltaic device according to claim 26, wherein the fourth polycrystalline silicon layer has the same crystallographic orientation as the third polycrystalline silicon layer.

31. (New) The crystalline silicon thin film photovoltaic device according to claim 26, wherein the third and fourth polycrystalline silicon layers contain not less than 0.1% of hydrogen.

32. (New) The crystalline silicon thin film photovoltaic device according to claim 25, wherein the third and fourth polycrystalline silicon layers contain not less than 0.1% of hydrogen.

- 33. (New) The crystalline silicon thin film photovoltaic device according to claim 21, wherein the first polycrystalline silicon layer is formed directly on the surface of the conductive substrate or the conductive layer.
- 34. (New) The crystalline silicon thin film photovoltaic device according to claim 1, wherein the amorphous silicon layer is formed directly on the surface of the conductive substrate or the conductive layer.

File No.: 521.41463X00 Client Ref.: PHCF-01103

35. (New) The crystalline silicon thin film photovoltaic device according to claim 11, wherein the amorphous silicon layer is formed directly on the surface of the

conductive substrate or the conductive layer.

36. (New) The crystalline silicon thin film photovoltaic device according to

claim 13, wherein the amorphous silicon layer is formed directly on the electrode of

the insulating substrate.

37. (New) The crystalline silicon thin film photovoltaic device according to

claim 17, wherein the amorphous silicon layer is disposed directly on the surface of

the conductive substrate or the conductive layer.